## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10525966	SHOJI ET AL.
Examiner	Art Unit
Flores, Leon	2611

SEARCHED			
Class	Subclass	Date	Examiner
375	132, 133, 135, 136	11/5/2007	LF

SEARCH NOTES				
Search Notes	Date	Examiner		
Consulted with SPE David Payne in regards to the patentability of the claims.	11/13/2007	LF		
Checked for possible double patenting.	10/20/2007	LF		
Consulted with SPE David Payne in regards to the amendments.	6/27/2008	LF		
Consulted with SPE David Payne in regards to the RCE.	12/5/2008	LF		
Consulted with SPE Shuwang Liu in regards to the references used to reject the claims.	5/29/2009	LF		
Consulted with SPE David Payne in regards to the new ground of rejection.	11/25/2009	LF		
Consulted with SPE David Payne in regards to the amendments.	5/17/2010	LF		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
375	130, 132, 133, 134, 135, 136, 137	5/17/2010	LF

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